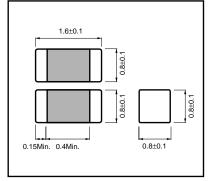
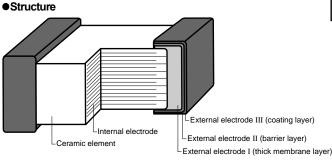
Multi-layer ceramic chip capacitors MCH18 (1608 (0603) size, chip capacitor)

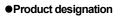
Features

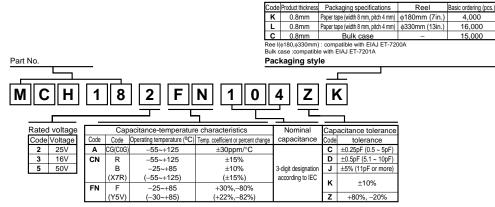
- 1) Small size (1.6 x 0.8 x 0.8 mm) makes it perfect for lightweight portable devices.
- Comes packed either in tape to enable automatic mounting or in bulk cases.
- Precise uniformity of shape and dimentions highly efficient automatic mounting.
- 4) Barrier layer and end terminations to improve solderability.







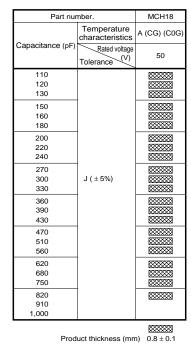






Capacitance range

For thermal compensation				
Part nu	MCH18			
Capacitance(pF)	Temperature characteristics	A (CG) (C0G)		
Capacitarice(pr)	Rated voltage Tolerance (V)	50		
0.5		×××××		
0.75				
1	-			
1.1 1.2				
1.2				
1.5				
1.6				
1.8				
2 2.2 2.4	C (±0.25pF)			
2.7				
2.7 3 3.3 3.6 3.9 4 4.3				
	-			
4.7				
5				
5.1				
5.6 6				
6.2				
6.8				
7	D (± 0.5pF)			
7.5				
8 8.2				
9	-			
9.1				
10				
11				
12 13				
15				
16				
18	-			
20				
22 24				
27	-			
30				
33	J(±5%)			
36 39				
39 43				
47				
51				
56				
62 68				
75				
82	1			
91				
100				



*The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.



MCH18

High dielectric constant

Part num	ber			MCH18		
Capacitance(pF)	Temperature characteristics	CN (R) (B) (X7R)		FN (F) (Y5V)		
Capacitance(pr)	Rated voltage (V)	50	25	50	25	16
	Tolerance	K (±	10%)	Z	(+80%, -20	%)
220		\otimes				
270 330		××××				
390						
470						
560 680						
820						
1,000						
1,200						
1,500 1,800						
2,200						
2,700		NXXXXX				
3,300 3,900						
4,700		××××		××××		
5,600						
6,800 8,200						
8,200 10,000 (0.01μF)				××××		
12,000						
15,000						
18,000 22,000						
27,000		******		******		
33,000				-		
39,000 47,000				****		
56,000				XXXXXX		
68,000						
82,000 100,000 (0.1μF)						
120,000					-	
150,000						
180,000						
220,000 270,000						
330,000						
390,000						
470,000 560,000						
680,000						
1,000,000 (1µF) 1,200,000						
1,500,000						
1,800,000 2,200,000						
2,200,000						

Product thickness (mm) 0.8 ± 0.1

Characteristics

Class 1 (For thermal compensation)

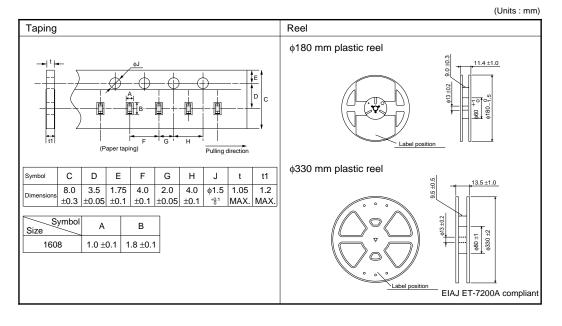
Temperature characteristics A (CG) (C0G)		Test methods / conditions (based on JIS C 5102)		
Item		()	(based on JIS C 5102)	
Operating temperature		−55°C ~ +125°C		
Nominal capacitance (C)		Must be within the specified tolerance range.	Based on paragraph 7.8 and paragraph 9 Measured at room temperature and standard humidity. 1000pF or less Measurement frequency : 1± 0.1MHz	
Dissipation factor $(\tan \delta)$		100 / (400 + 20C)% or less (Less than 30 pF) 0.1% or less (30 pF or larger)	Measurement voltage : 1± 0.1Vrr Over 1000pF Measurement frequency : 1± 0.1kH. Measurement voltage : 1± 0.1Vrr	
Insulation resistance (IR)		$10{,}000M\Omega$ or $500M\Omega{\cdot}\mu F$, whichever is smaller	Based on paragraph 7.6 Measurement is made after rated voltage is applied for 60 \pm 5s.	
Withstanding voltage		The insulation must not be damaged.	Based on paragraph 7.1 Apply 300% of the rated voltage for 1 to 5s then measure.	
Temperature cl	haracteristics	Within 0 \pm 30ppm / $^{\circ}\text{C}$	The temperature coefficients in table 12, paragraph 7.12 are calculated at 20°C and high temperature.	
Terminal adher	ence	No detachment or signs of detachment.	Based on paragraph 8.11.2 Apply 5N for 10 \pm 1s in the direction indicated by the arrow. Pressure (5N) Capacitor	
Resistance to vibration	Appearance	There must be no mechanical damage.	Chip is mounted to a board in the	
	Rate of capacitance change	Must be within initial tolerance.	to vibration (type A in paragraph 8.2),	
	Dissipation factor (tano)	Must satisfy initial specified value.	and measured 24 \pm 2 hrs. later. Board	
Solderability		At least 3 / 4 of the surface of the two terminals must be covered with new solder.	Based on paragraph 8.13 Soldering temperature : 235 ± 5°C Soldering time : 2 ± 0.5s	
	Appearance	There must be no mechanical damage.		
	Rate of capacitance change	\pm 2.5% or \pm 0.25 pF , whichever is larger.	Based on paragraph 8.14	
Resistance to soldering	Dissipation factor (tanδ)	Must satisfy initial specified value.	Soldering temperature : $260 \pm 5^{\circ}$ C Soldering time : 5 ± 0.5 s	
heat	Insulation resistance	10,000M\Omega or $500 M\Omega {\cdot} \mu F$, whichever is smaller	Preheating : 150 ± 10°C for 1 to 2 min.	
	Withstanding voltage	The insulation must not be damaged.	1.02.1111.	
Temperature cycling	Appearance	There must be no mechanical damage.		
	Rate of capacitance change	\pm 2.5% \pm 0.25 pF , whichever is larger.	Based on paragraph 9.3 Number of cycles : 5 Capacitance measured after 24 ± 2 h	
	Dissipation factor (tano)	Must satisfy initial specified value.		
	Insulation resistance	10,000M\Omega or $500 M\Omega {\cdot} \mu F$, whichever is smaller		
Humidity load - test	Appearance	There must be no mechanical damage.	Based on paragraph 9.9 Test temperature : 40 ± 2°C Relative humidity : 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs.	
	Rate of capacitance change	\pm 7.5% or \pm 0.75 pF , whichever is larger.		
	Dissipation factor (tanδ)	0.5% or less		
	Insulation resistance	$500 M\Omega$ or $25 M\Omega \cdot \mu F$, whichever is smaller	Capacitance measured after 24 ± 2 hrs.	
	Appearance	There must be no mechanical damage.	Based on paragraph 9.10 Test temperature : Max. operating temp Applied voltage : rated voltage × 200% Test time : 1,000 to 1,048 hrs.	
High-	Rate of capacitance change	\pm 3.0% or \pm 0.3 pF , whichever is larger.		
temperature load test	Dissipation factor (tanδ)	0.3% or less		
	Insulation resistance	1,000M\Omega or $50M\Omega{\cdot}\mu\text{F}$, whichever is smaller	Capacitance measured after 24 \pm 2 hrs.	

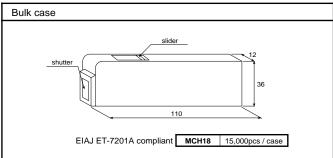


	Temperature characteristics			Test methods/conditions	
Item		CN (R) (B) (X7R)	FN (F) (Y5V)	(based on JIS C 5102)	
Operating temperature		−55°C ~ +125°C	−30°C ~ +85°C		
Nominal capacitance (C)		Must be within the specified tolerance range.		Based on paragraph 7.8 Measured at room temperature and standard humid	
Dissipation factor (tanδ)		2.5% or less 5.0% or less Measurement frequen		Measurement frequency: 1 ± 0.1 kHz	
Insulation resistance (IR)		10,000 M\Omega or 500 M\Omega $\cdot\mu\text{F},$ whichever is smaller		Based on paragraph 7.6 Measurement is made after rated voltage is applied for $60 \pm 5s$.	
Withstanding voltage		The insulation must not be damaged.		Based on paragraph 7.1 Apply 250% of the rated voltage for 1 to 5s then measu	
Temperature cl	haracteristics	Within ± 15%	+ 22, + 82%	The temperature coefficients in paragraph 7.12 table 8, condition B, are based on measuremen carried out at 20°C, with no voltage applied.	
Terminal adherence No detachment or signs of detachment		Based on paragraph 8. 11. 2. Apply 5N for 10 \pm 1s in the direction indicated by the arrow. Experimental terms of the terms of terms			
	Appearance	There must be no mechanical damage.		Chip is mounted to a board in the	
Resistance to vibration	Rate of capacitance change	e Must be within initial tolerance.		manner shown on the right, subjected to vibration (type A in paragraph 8.2),	
	Dissipation factor $(tan\delta)$	Must satisfy initial specified value.		and measured 48 ± 4 hrs. later. Board	
Solderability	At least 3/4 of the surface of the two terminals must be covered with new solder.		Based on paragraph 8. 13 Soldering temperature: $235 \pm 5^{\circ}$ C Soldering time : 2 ± 0.5 s		
	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	Within ± 5.0% Within ± 20.0%		Record on percercets 9, 14	
Resistance to soldering	Dissipation factor $(tan\delta)$	Must satisfy initial specified value.		Based on paragraph 8. 14. Soldering temperature: 260 ± 5°C	
heat	Insulation resistance	10,000M\Omega or 500M\Omega $\cdot\mu\text{F},$ whichever is smaller			
	Withstanding voltage	The insulation must not be damaged.			
	Appearance	There must be no n	nechanical damage.		
Temperature	Rate of capacitance change	Within ± 7.5%	Within ± 20.0%	Based on paragraph 9.3 Number of cycles : 5	
cycling	Dissipation factor (tan)	Must satisfy initial specified value.		Capacitance measured after 48 ± 4 h	
	Insulation resistance	10,000M\Omega or 500M\Omega $\cdot\mu\text{F},$ whichever is smaller		1	
Humidity load test	Appearance	There must be no mechanical damage.		Based on paragraph 9.9	
	Rate of capacitance change	± 12.5% or less	Within ± 30.0%	Test temperature : 40 ± 2°C	
	Dissipation factor (tan)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Relative humidity: 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs.	
	Insulation resistance	500M Ω or 25M $\Omega \cdot \mu F$, whichever is smaller		Capacitance measured after 48 \pm 4 h	
High- temperature load test	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	Within ± 10.0%	Within ± 30.0%	Based on paragraph 9.10	
	Dissipation factor (tan)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Test temperature : Max. operating ter Applied voltage : rated voltage × 20 Test time : 1,000 to 1,048 hrs	
	Insulation resistance	1,000MΩ or 50MΩ · μ F, whichever is smaller		Capacitance measured after 48 ± 4	



Packaging specifications

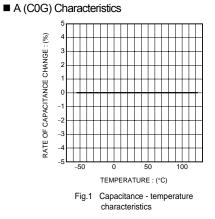




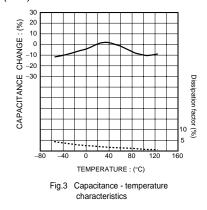


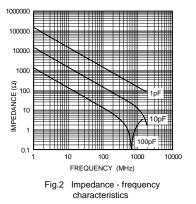
Ceramic capacitors

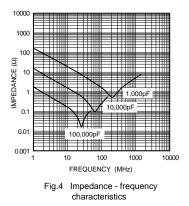
Electrical characteristics

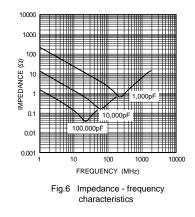


■CN (X7R) Characteristics









■FN (Y5V) Characteristics

10

-10 -20

-30 -40

-50 -60

-70

-80

-80 -40 0 40

CAPACITANCE CHANGE : (%)



Dissipation factor (%)

60

10

80 120 160

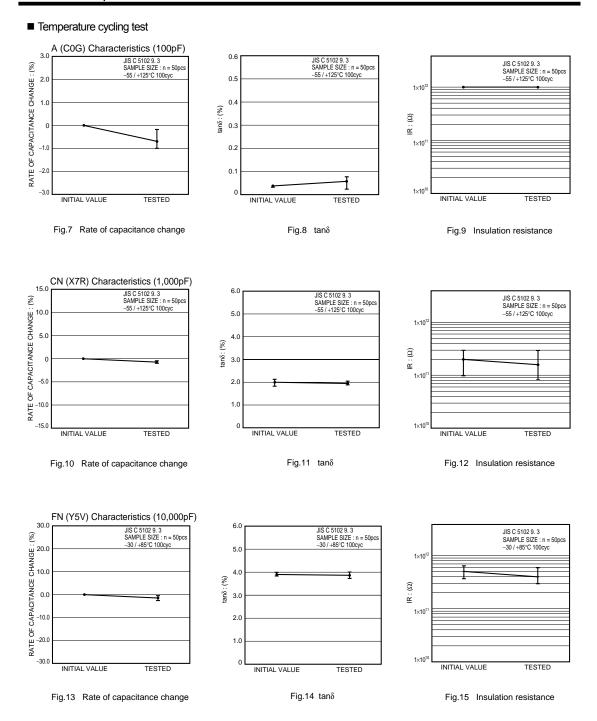
TEMPERATURE : (°C)

Fig.5 Capacitance - temperature

characteristics

ROHM

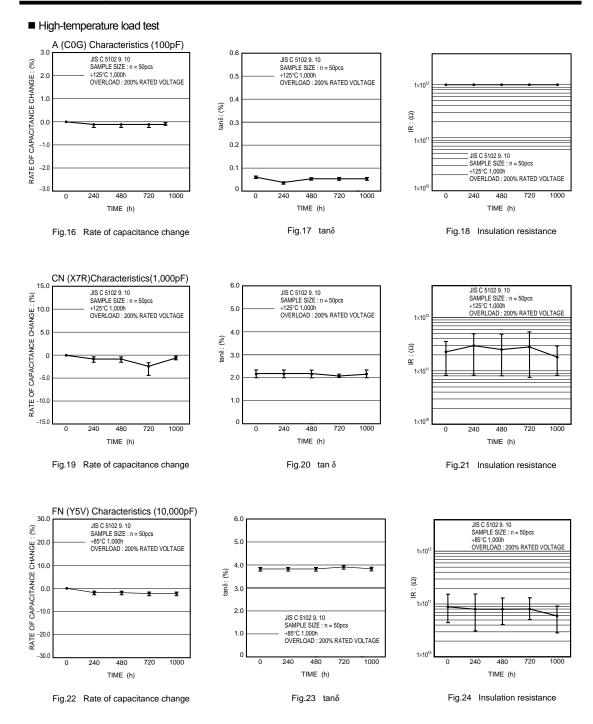
Ceramic capacitors



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ROHM

Ceramic capacitors





Ceramic capacitors

